Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/734,297	OHGANE ET AL.	
Examiner	Art Unit	
Tae H. Yoon	1714	

SEARCHED					
Class	Subclass	Date	Examiner		
524	494	8-18-06	4		
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ΓΝΊ	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST Inventor Search	f-27-06	N		
Inventor Search				
GAT	1/2/07	2		